

**Search Notes**

Application/Control No.

10/618,816

Examiner

Vuthe Siek

Applicant(s)/Patent under  
Reexamination

PANG ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	4-6, 19-21	5/4/2005	VS
703	13	5/4/2005	VS
702	59,81	5/4/2005	VS
430	5	5/4/2005	VS
382	144,145	5/4/2005	VS
382	149	5/4/2005	VS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST ALL DATABASES, IEEE, GOOGLE	5/4/2005	VS